

Panel Session 1: VERIFICATION & TEST

Invited Panelists:

Yoshihiro Miyazaki, *Executive Chief Engineer, Hitachi Automotive*

Functional Safety

Sumio Morioka, *Expert, NEC Central Research Lab*

Information Security

Koichiro Takayama, *Fujitsu Limited*

VLSI Design Verification

JST/CREST DVLSI Researchers:

Masahiro Fujita, *Prof., University of Tokyo*

Makoto Sugihara, *Assoc. Prof., Kyushu University*

Seiji Kajihara, *Prof., Kyushu Institute of Technology*

Takeshi Fujino, *Prof., Ritsumeikan University*

**DEPENDABILITY=Reliability + Maintainability + Availability
+ Information Security + Functional Safety**



VLSI User

Oops! What's up!

Information Security



Design Bugs



Aging



Soft error

Functional Safety



VLSIs are no longer dependable?

Q1 What are dependability indices of VLSIs (and their application systems)?

Q2 How do you apply them to your work?

Obesity Indices



Body Mass Index:

$$BMI = \frac{M}{L^2}$$

Metabolic Syndrome Criteria:

$$Waist \geq 85(90)cm$$